

#### 30V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

## **Product Summary**

Device	V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> max	<b>I</b> <sub>D</sub> max T <sub>A</sub> = 25°C (Notes 4 & 7)
01	30V	3.7A	
Q1	307	$180$ m $\Omega$ @ V <sub>GS</sub> = $4.5$ V	3.0A
Q2	-30V	210mΩ @ V <sub>GS</sub> = -10V	
Q2		$330\text{m}\Omega$ @ V <sub>GS</sub> = -4.5V	-2.2A

## **Description and Applications**

This MOSFET has been designed to minimize the on-state resistance  $(R_{DS(on)})$  and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- MOSFET gate drive
- LCD backlight inverters
- Motor control
- Portable applications

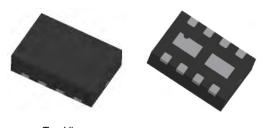
#### **Features and Benefits**

- Low profile package, for thin applications
- Low R<sub>θJA</sub>, thermally efficient package
- 6mm² footprint, 50% smaller than TSOP6 and SOT23-6
- Low on-resistance
- Fast switching speed
- "Lead-Free", RoHS Compliant (Note 1)
- Halogen and Antimony Free. "Green" Device (Note 2)
- Qualified to AEC-Q101 Standards for High Reliability

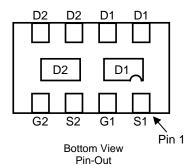
#### **Mechanical Data**

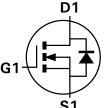
- Case: DFN3020B-8
- Terminals: Pre-Plated NiPdAu leadframe
- Nominal package height: 0.8mm
- UL Flammability Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Solderable per MIL-STD-202, Method 208
- Weight: 0.013 grams (approximate)

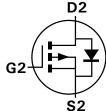
## DFN3020B-8



Top View Bottom View







Q1 N-Channel

Q2 P-Channel

**Equivalent Circuit** 

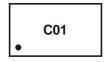
### **Ordering Information** (Note 3)

ĺ	Part Number	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
	ZXMC3AMCTA	C01	7	8	3000

Notes:

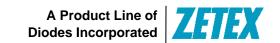
- 1 No purposefully added lead
- 2. Diodes Inc's "Green" policy can be found on our website at http://www.diodes.com.
- 3. For packaging details, go to our website at http://www.diodes.com.

### **Marking Information**



C01 = Product Type Marking Code Top view, Dot Denotes Pin 1





## Maximum Ratings @TA = 25°C unless otherwise specified

C	Symbol	N-channel – Q1	P-channel – Q2	Unit		
Drain-Source Voltage			$V_{DSS}$	30	-30	<b>V</b>
Gate-Source Voltage			$V_{GSS}$	±20	±20	V
		(Notes 4 & 7)		3.7	-2.7	
Continuous Drain Current	$V_{GS} = 10V$	T <sub>A</sub> = 70°C (Notes 4 & 7)	I <sub>D</sub>	3.0	-2.2	^
		(Notes 3 & 7)		2.9	-2.1	A
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 6 & 7)	I <sub>DM</sub>	13	-9.2	
Continuous Source Current (Body diode) (Notes 4 & 7)		Is	3.2	-2.8		
Pulse Source Current (Body diode) (Notes 6 & 7)			I <sub>SM</sub>	13	-9.2	

## Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic		Symbol	N-channel – Q1 P-channel – Q2	Unit	
	(Notes 3 & 7)		1.50 12	W	
Power Dissipation	(Notes 4 & 7)		2.45 19.6		
Linear Derating Factor	(Notes 5 & 7)	P <sub>D</sub>	1.13 9	mW/°C	
	(Notes 5 & 8)		1.70 13.6	1	
	(Notes 3 & 7)		83.3		
The second Descriptions of Australia	(Notes 4 & 7)		51.0		
Thermal Resistance, Junction to Ambient	(Notes 5 & 7)	R <sub>0JA</sub>	111	°C/W	
	(Notes 5 & 8)		73.5		
Thermal Resistance, Junction to Lead (Notes 7 & 9)		$R_{\theta JL}$	17.1		
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C		

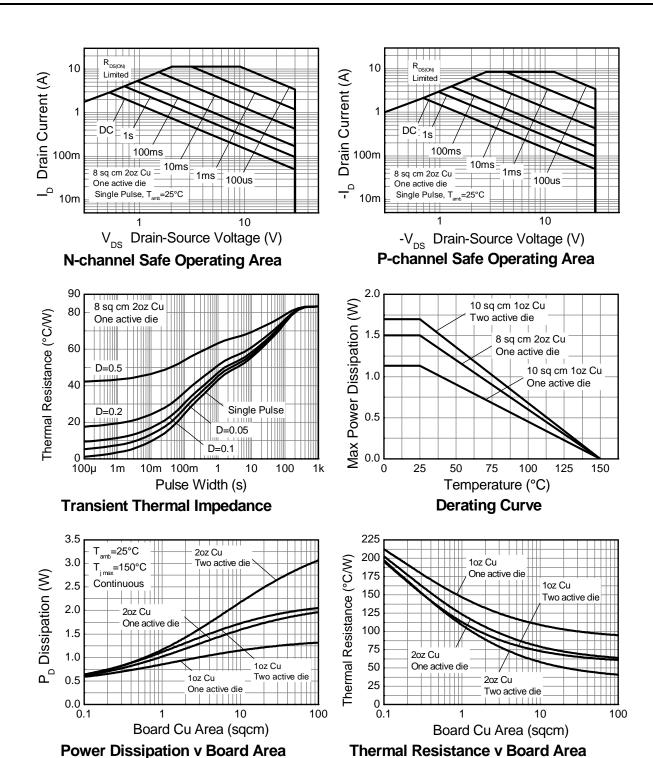
#### Notes:

- 3. For a device surface mounted on 28mm x 28mm (8cm²) FR4 PCB with high coverage of single sided 2oz copper, in still air conditions; the device is measured when operating in a steady-state condition. The heatsink is split in half with the exposed drain pads connected to each half.
- 4. Same as note (3) except the device is measured at t < 5 sec.

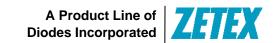
  5. Same as note (3), except the device is surface mounted on 31mm x 31mm (10cm²) FR4 PCB with high coverage of single sided 1oz copper.
- 6. Same as note (3), except the device is pulsed with D = 0.02 and pulse width 300µs. The pulse current is limited by the maximum junction temperature.
- 7. For a dual device with one active die.
- 8. For dual device with 2 active die running at equal power.
- 9. Thermal resistance from junction to solder-point (at the end of the drain lead).



#### **Thermal Characteristics**







## Electrical Characteristics – Q1 N-Channel @TA = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test C	Condition
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	0.5	μА	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	-	3.0	V	$I_D = 250 \mu A, V_D$	s = V <sub>GS</sub>
Static Drain-Source On-Resistance (Note 10)			0.100	0.120	Ω	$V_{GS} = 10V, I_D =$	= 2.5A
Static Drain-Source On-Resistance (Note 10)	R <sub>DS (ON)</sub>	-	0.140	0.180	12	$V_{GS} = 4.5V, I_D$	= 2.0A
Forward Transconductance (Note 10 & 11)	g <sub>fs</sub>	-	3.5	-	S	$V_{DS} = 10V, I_D = 2.5A$	
Diode Forward Voltage (Note 10)	V <sub>SD</sub>	-	0.85	0.95	V	$I_S = 1.7A, V_{GS}$	= 0V
Reverse Recover Time (Note 11)	t <sub>rr</sub>	-	17.7	-	ns	I <sub>S</sub> = 2.5A, di/dt= 100A/µs	
Reverse Recover Charge (Note 11)	Q <sub>rr</sub>	-	13.0	-	nC	$I_S = 2.5A$ , $I_S = 2.5A$	= 100A/μS
DYNAMIC CHARACTERISTICS (Note 11)							
Input Capacitance	C <sub>iss</sub>	-	190	-	pF	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	-	38	-	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	20	-	pF	1 = 1.01/11/12	
Total Gate Charge (Note 12)	Qg	-	2.3	-	nC	$V_{GS} = 4.5V$	
Total Gate Charge (Note 12)	Qq	-	3.9	-	nC		$V_{DS} = 15V$
Gate-Source Charge (Note 12)	Q <sub>gs</sub>	-	0.6	-	nC	$V_{GS} = 10V$	$I_D = 2.5A$
Gate-Drain Charge (Note 12)	Q <sub>gd</sub>	-	0.9	-	nC	7	
Turn-On Delay Time (Note 12)	t <sub>D(on)</sub>	-	1.7	-	ns		
Turn-On Rise Time (Note 12)	t <sub>r</sub>	-	2.3	-	ns	V <sub>DS</sub> = 15V, I <sub>D</sub> =	= 2.5A
rn-Off Delay Time (Note 12) $t_{D(off)}$ - 6.6 - ns $V_{GS} = 10V$ ,		V <sub>GS</sub> = 10V, R <sub>G</sub>	= 6Ω				
Turn-Off Fall Time (Note 12)	t <sub>f</sub>	-	2.9	-	ns		

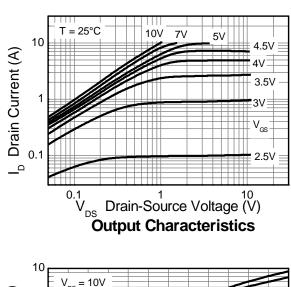
Notes:

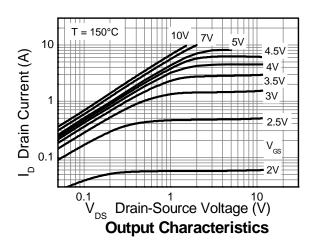
- 10. Measured under pulsed conditions. Width  $\leq$  300 $\mu$ s. Duty cycle  $\leq$  2%.
- 11. For design aid only, not subject to production testing.

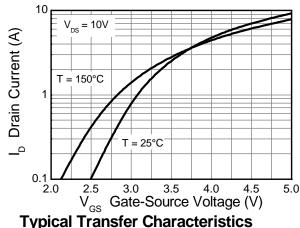
  12. Switching characteristics are independent of operating junction temperature.

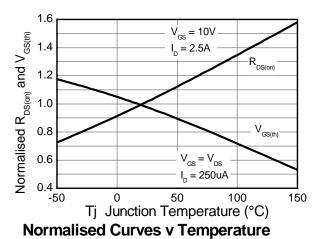


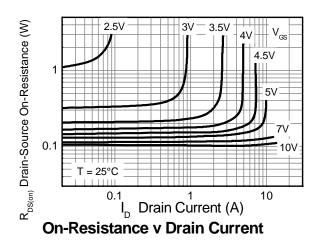
## Typical Electrical Characteristics – Q1 N-Channel

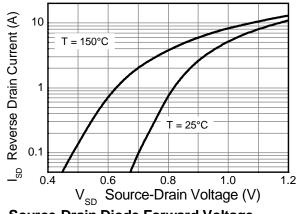








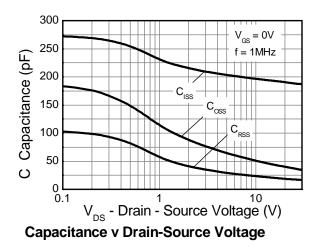


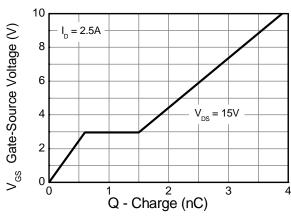


Source-Drain Diode Forward Voltage



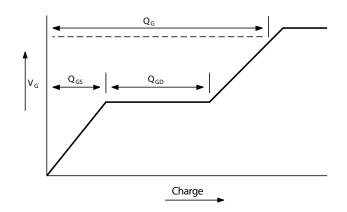
## Typical Electrical Characteristics - Q1 N-Channel - Continued





Gate-Source Voltage v Gate Charge

## **Test Circuits**



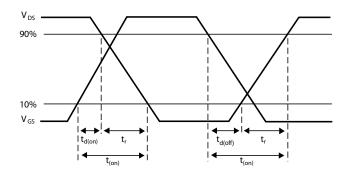
Current regulator

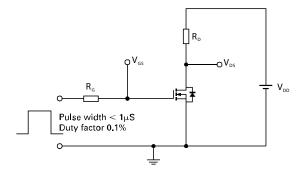
12V 0.2µF 50k D.U.T

Vos

Basic gate charge waveform

Gate charge test circuit

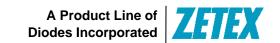




Switching time waveforms

Switching time test circuit





## Electrical Characteristics – Q2 P-Channel @TA = 25°C unless otherwise specified

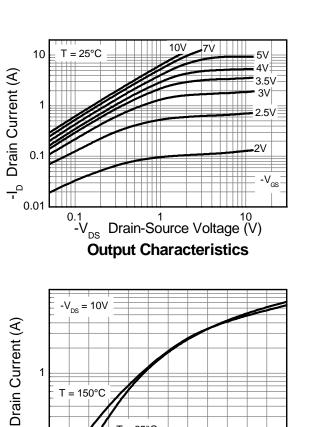
Characteristic	Symbol	Min	Тур	Max	Unit	Test C	Condition
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	-	-	V	$I_D = -250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	-0.5	μΑ	V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1.0	-	-3.0	V	$I_D = -250 \mu A, V_1$	$DS = V_{GS}$
Static Drain-Source On-Resistance (Note 13)	Ь		0.150	0.210	Ω	$V_{GS} = -10V, I_D$	= -1.4A
Static Drain-Source Off-Resistance (Note 13)	R <sub>DS (ON)</sub>	-	0.280	0.330	12	$V_{GS} = -4.5V, I_{D}$	e -1.1A
Forward Transconductance (Note 13 & 14)	<b>g</b> fs	-	2.48	-	S	V <sub>DS</sub> = -15V, I <sub>D</sub> = -1.4A	
Diode Forward Voltage (Note 13)	$V_{SD}$	-	-0.85	-0.95	V	$I_S = -1.1A, V_{GS}$	; = 0V
Reverse Recover Time (Note 14)	t <sub>rr</sub>	-	18.6	-	ns	I <sub>S</sub> = -0.95A, di/dt = 100A/μs	
Reverse Recover Charge (Note 14)	$Q_{rr}$	-	14.8	-	nC IS = -0.95A, di/		$x = 100A/\mu s$
DYNAMIC CHARACTERISTICS (Note 14)							
Input Capacitance	C <sub>iss</sub>	-	206	-	pF	V <sub>DS</sub> = -15V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	-	59.3	-	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	49.2	-	pF	1 = 1.01/11/12	
Total Gate Charge (Note 15)	$Q_{g}$	-	3.8	-	nC	$V_{GS} = -4.5V$	
Total Gate Charge (Note 15)	Qq	-	6.4	-	nC		$V_{DS} = -15V$
Gate-Source Charge (Note 15)	$Q_{gs}$	-	0.69	-	nC	$V_{GS} = -10V$	$I_D = -1.4A$
Gate-Drain Charge (Note 15)	Q <sub>qd</sub>	-	2.0	-	nC	7 1	
Turn-On Delay Time (Note 15)	t <sub>D(on)</sub>	-	1.5	-	ns		
Turn-On Rise Time (Note 15)	t <sub>r</sub>	-	2.8	-	ns	$V_{DS} = -15V, I_{D}$	= -1A
Turn-Off Delay Time (Note 15)	t <sub>D(off)</sub>	-	11.3	-	ns	V <sub>GS</sub> = -10V, R <sub>0</sub>	3 = 6Ω
Turn-Off Fall Time (Note 15)	t <sub>f</sub>	-	7.5	-	ns		

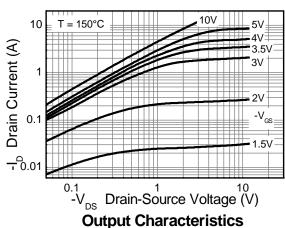
Notes:

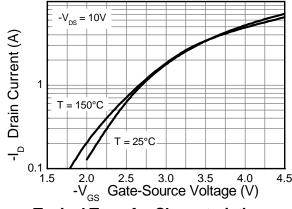
- 13. Measured under pulsed conditions. Width  $\leq$  300 $\mu$ s. Duty cycle  $\leq$  2%.
- 14. For design aid only, not subject to production testing.15. Switching characteristics are independent of operating junction temperature.

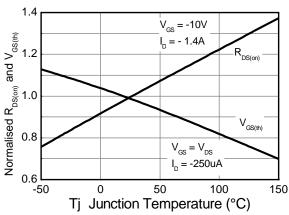


## Typical Electrical Characteristics - Q2 P-Channel

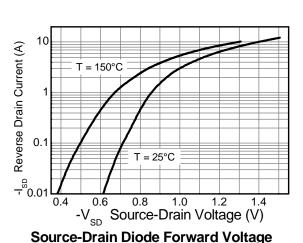




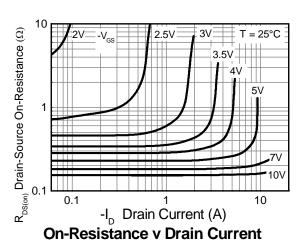




Typical Transfer Characteristics

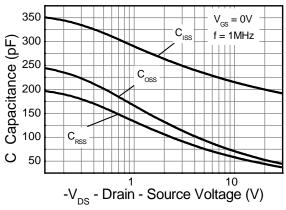


**Normalised Curves v Temperature** 

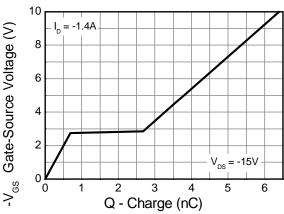




## Typical Electrical Characteristics - Q2 P-Channel - Continued

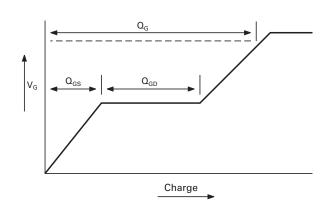


Capacitance v Drain-Source Voltage

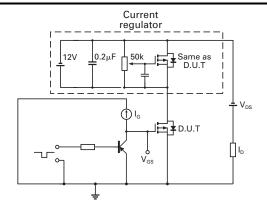


Gate-Source Voltage v Gate Charge

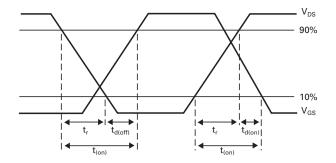
## **Test Circuits**



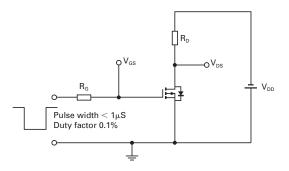
Basic gate charge waveform



Gate charge test circuit



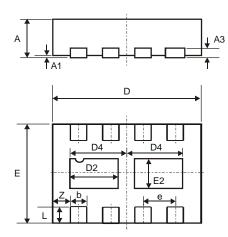
**Switching time waveforms** 



Switching time test circuit

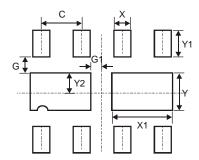


# **Package Outline Dimensions**



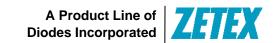
DFN3020B-8						
Dim	Min	Max	Тур			
Α	0.77	0.83	0.80			
A1	0	0.05	0.02			
А3	-	-	0.15			
b	0.25	0.35	0.30			
D	2.95	3.075	3.00			
D2	0.82	1.02	0.92			
D4	1.01	1.21	1.11			
е	-	-	0.65			
Е	1.95	2.075	2.00			
E2	0.43	0.63	0.53			
L	0.25	0.35	0.30			
Z	-	-	0.375			
All Dimensions in mm						

# **Suggested Pad Layout**



Dimensions	Value (in mm)
С	0.650
G	0.285
G1	0.090
X	0.400
X1	1.120
Y	0.730
Y1	0.500
Y2	0.365





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